

# AMT Status

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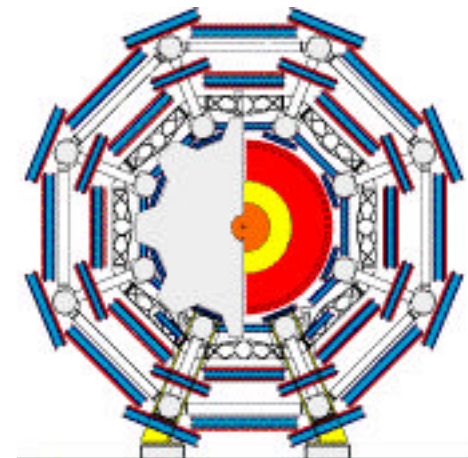
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<http://atlas.kek.jp/~arai/>

May 8, 2000

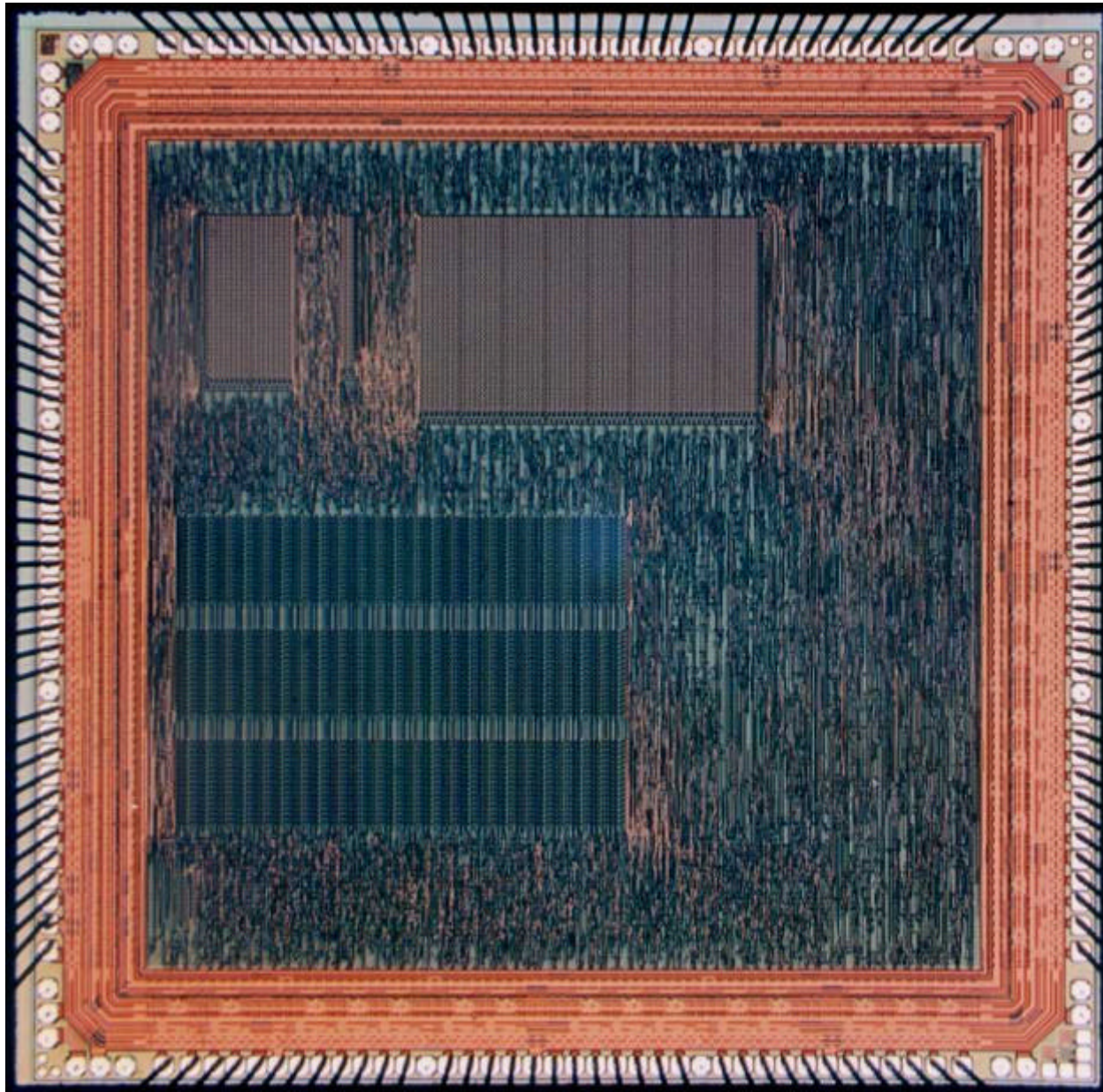
Muon Elec. W.S.@CERN

- End of Jan.:AMT-1 submitted
- End of Mar.:20 ceramic +200plastic packaged chip delivered.
- Testing
  - PLL stability
  - CSR read/write
  - JTAG I/F
  - Hit In -> Trigger -> Serial Out
  - Power Consumption



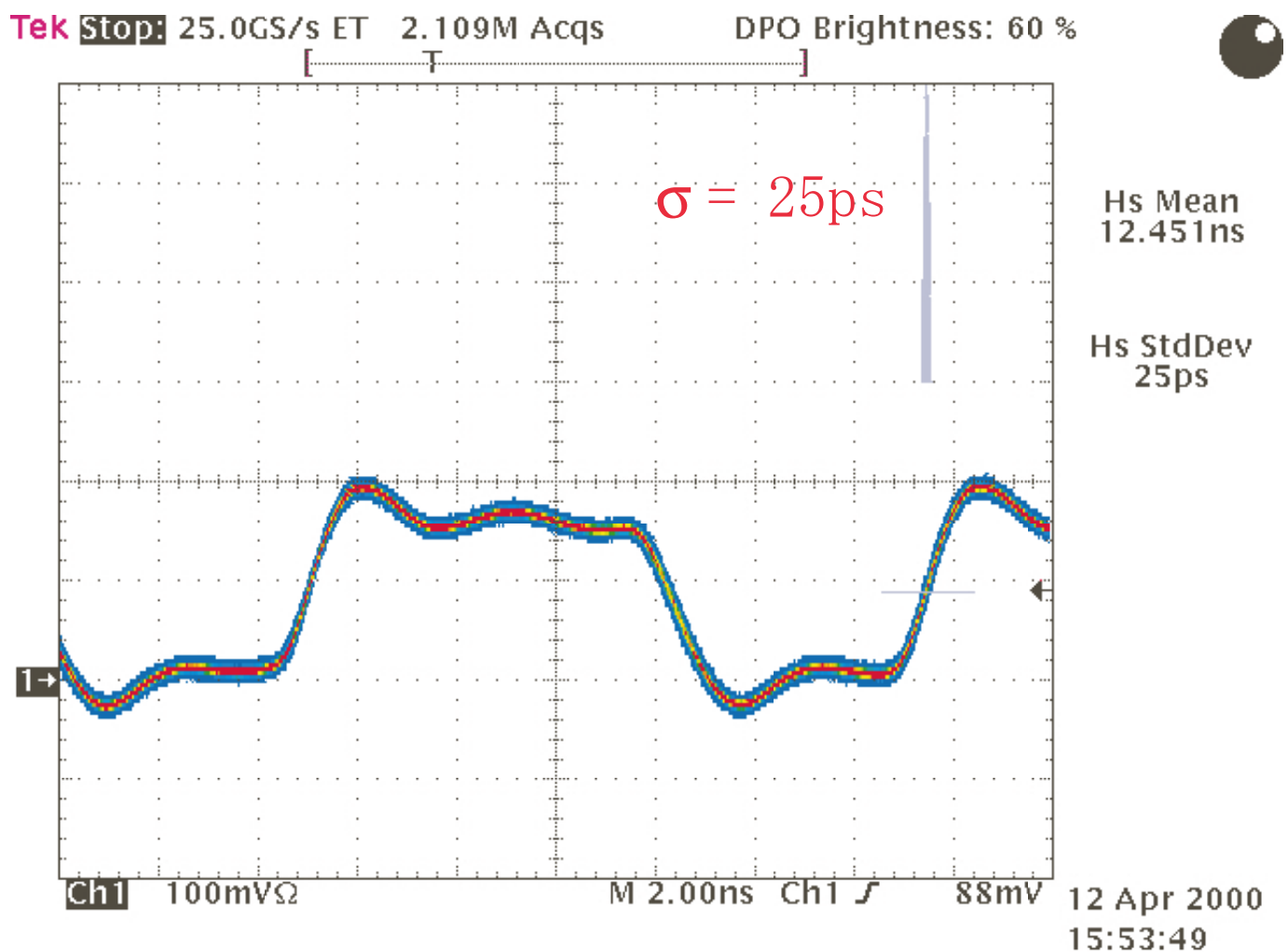
## AMT-1 Specification

- ★ Process :CMOS 0.3  $\mu\text{m}$  Gate Array (Toshiba TC220G)
- ★ No. of Gate Used :106 k gates (35% of master)
- ★ Control & Status Registers :12 bit x 21 (252 bits)
- ★ 24 channels, 0.78 ns/bit, 17 bit dynamic range
- ★ 256 word L1 Buffer, 64 word Readout FIFO
- ★ 4 word Channel buffer, 8 word Trigger FIFO
- ★ LVDS I/F, JTAG, BIST logic
- ★ Chip size : 6.4 mm x 6.4 mm
- ★ Package :0.5 mm pitch, 144pins QFP



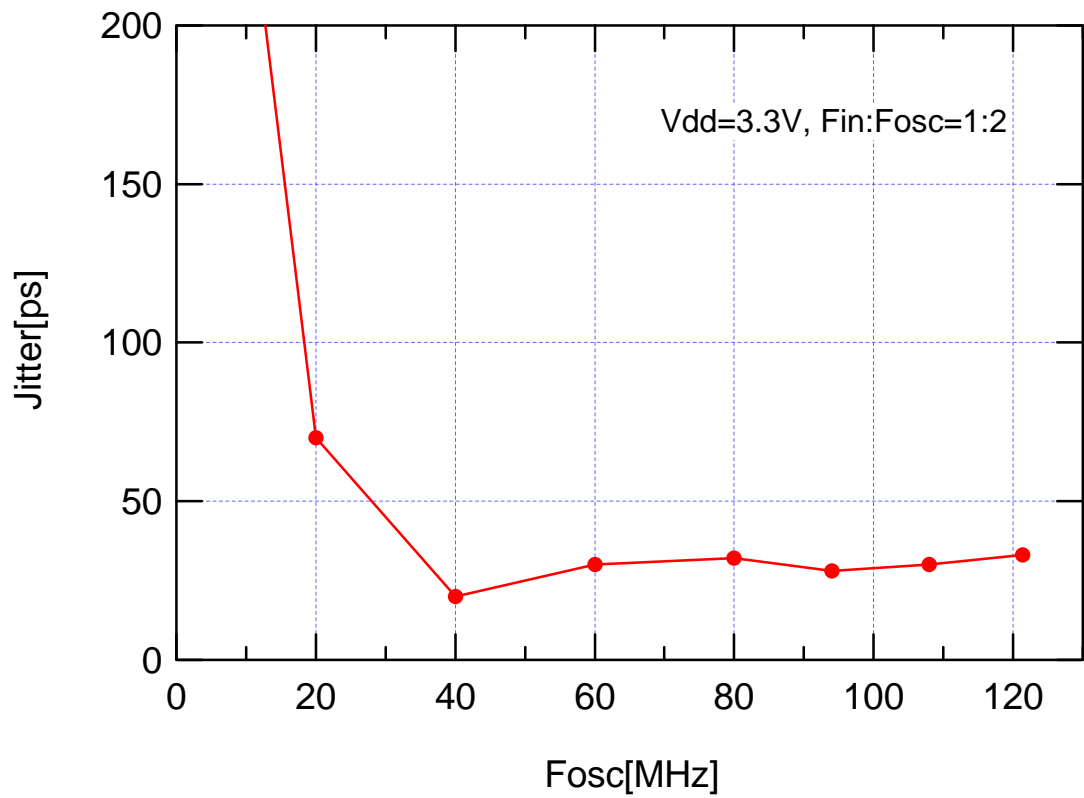
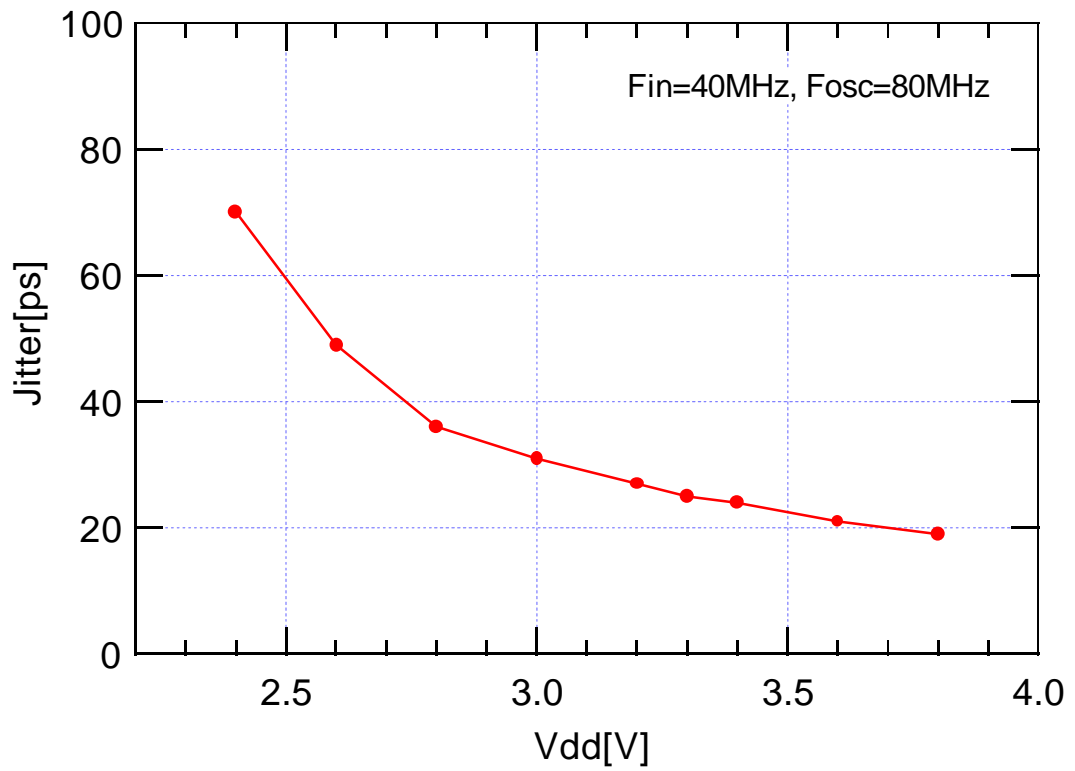
***Photograph of the AMT-1 chip***

# PLL Jitter



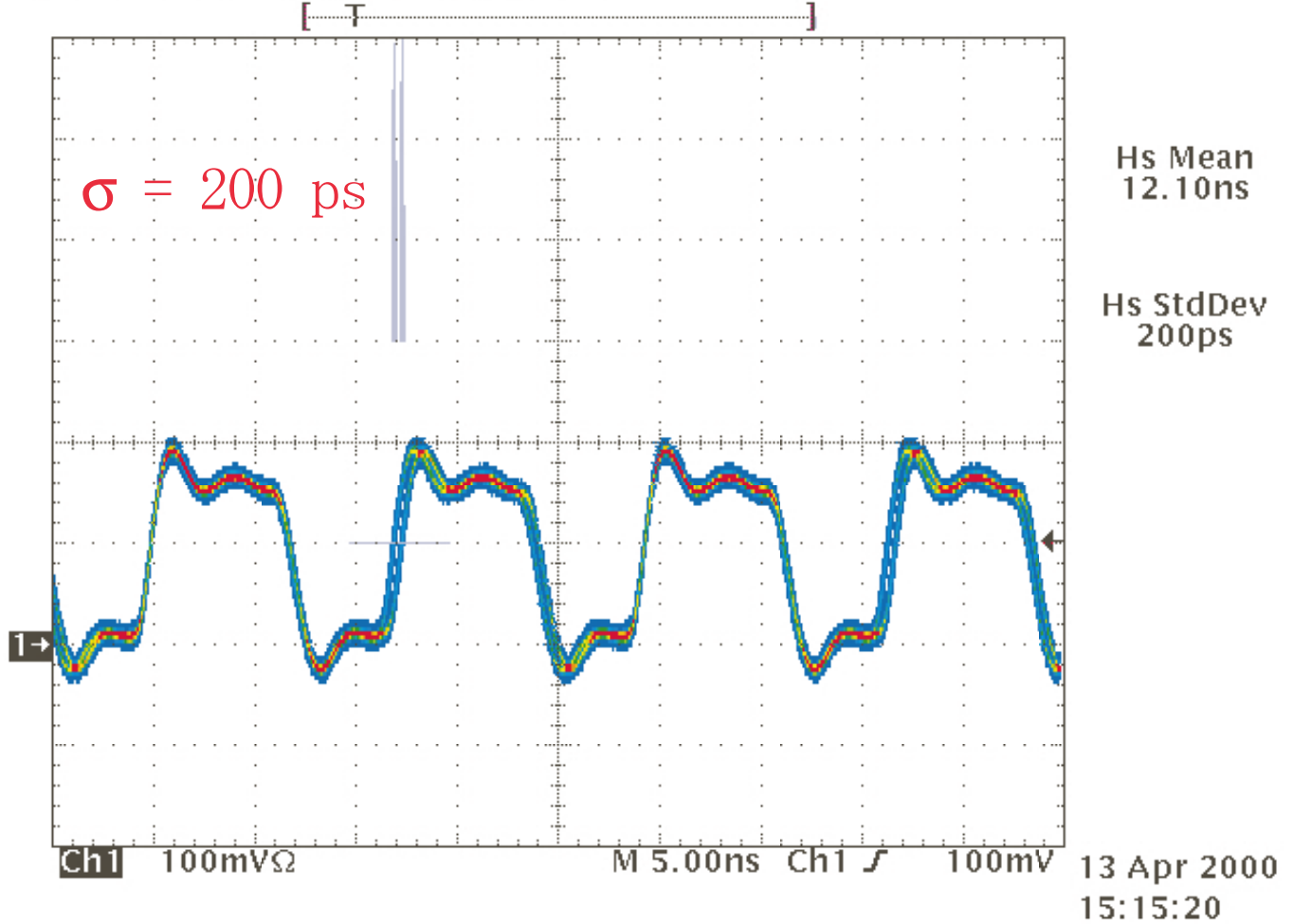
$F_{in} = 40\text{MHz}$ ,  $F_{osc} = 80\text{MHz}$

## PLL Jitter



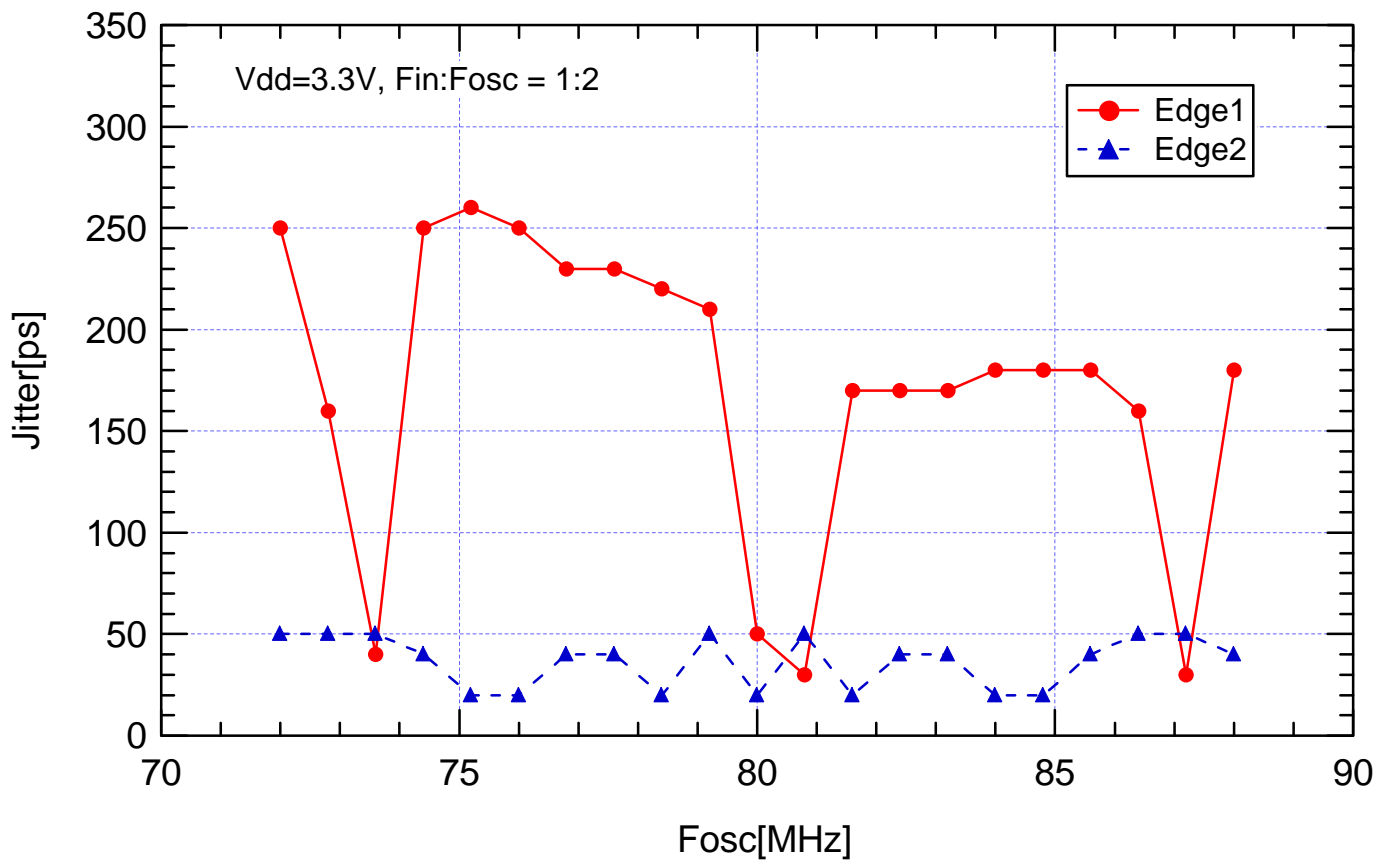
# PLL Jitter (Unstable Point)

Tek Stop: 10.0GS/s ET 2.580M Acqs



$F_{in} = 41 \text{ MHz}$ ,  $F_{osc} = 82 \text{ MHz}$

## PLL Jitter (1st Edge & 2nd Edge)

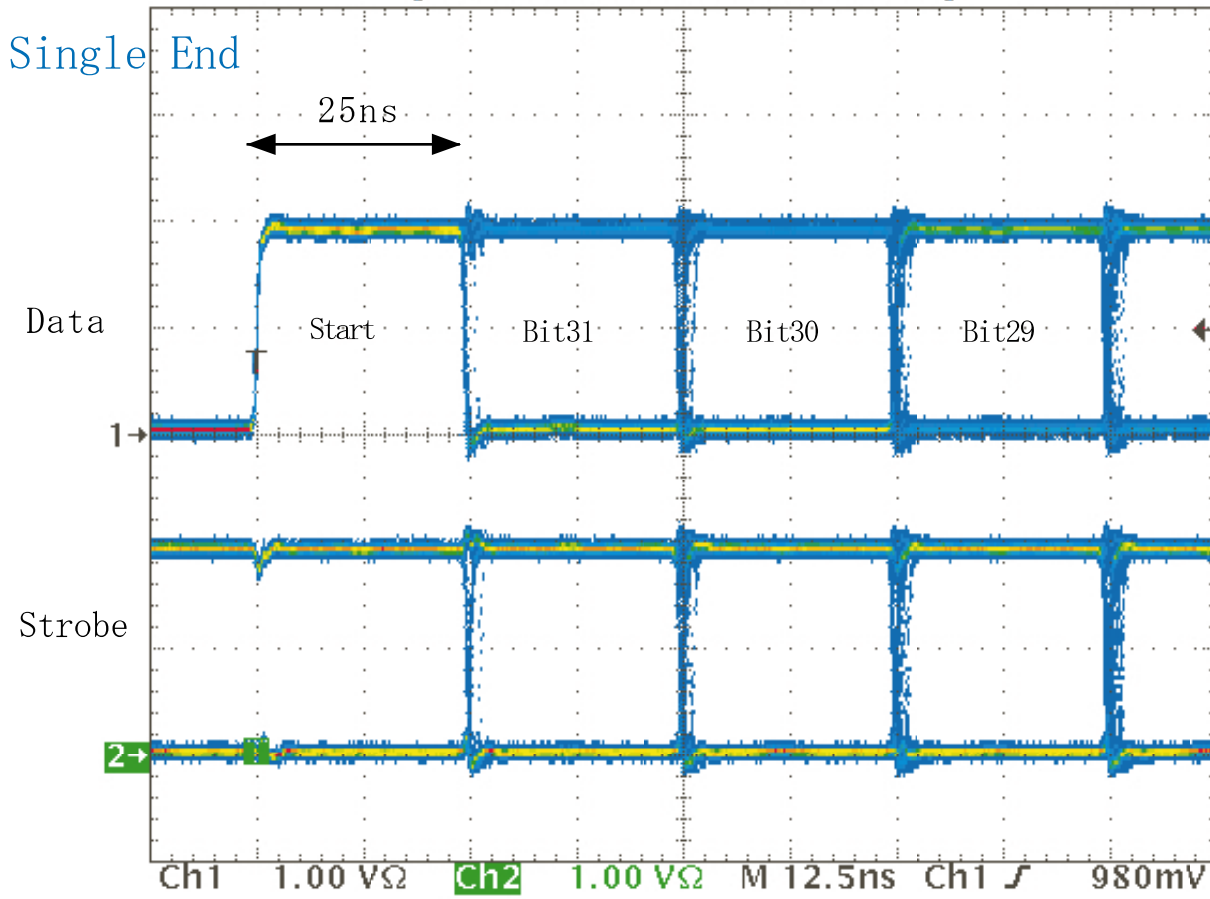


$$\begin{aligned} \sigma(\text{total}) &\approx \sigma(\text{digital}) \oplus (\sigma(\text{edge1}) + \sigma(\text{edge2}))/2 \\ &\approx 225 \text{ ps} \oplus (50 \text{ ps} + 250 \text{ ps})/2 \\ &\approx 270 \text{ ps} \end{aligned}$$

# LVDS Serial Output

Tek Stop: 4.00GS/s ET 211412 Acqs

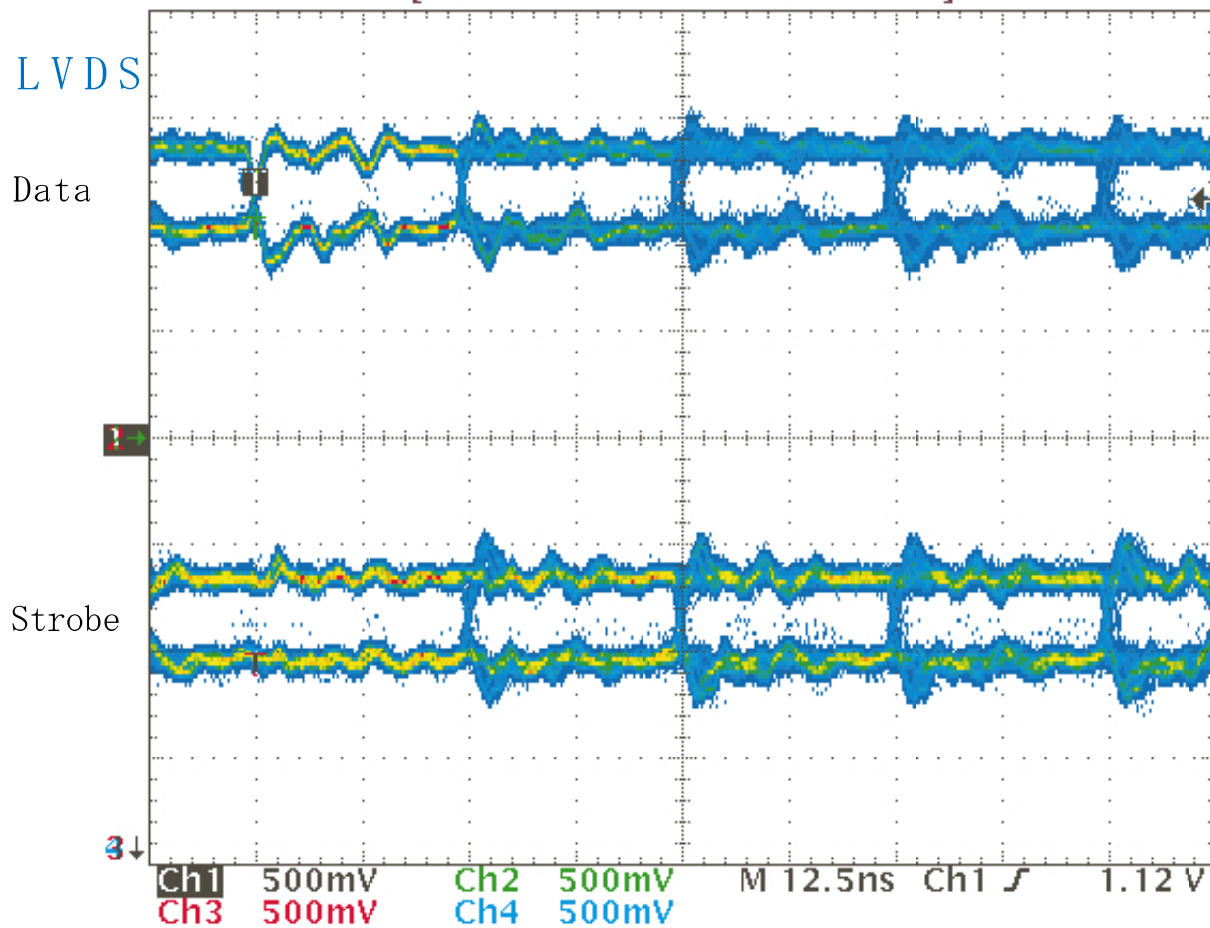
DPO Brightness: 4 %



25 Apr 2000  
16:26:38

Tek Stop: 4.00GS/s ET 138221 Acqs

DPO Brightness: 4 %



25 Apr 2000  
16:22:06

00.05.02 Y.A.



## Power Consumption

### Simulation:

400 mW (Internal Circuit)  
+ 480 mW (16mW x 30 LVDS receivers)  
= ~900 mW/chip

### Measurement:

3.3V x 148 mA = 488 mW/chip (20mW/chan)  
(@400kHz hit, 100kHz Trigger)

### LVDS receiver:

New Low Power design will be designed at Toshiba.  
Thus more reduction in power is expected.

## AMT Schedule

- ◆ 98.12 AMT-0 (Evaluation Chip) produced (1,000 chips)
- ◆ 98.12 AMT-TEG (Test Element Chip) produced
- ◆ 99. 6 AMT-TEG Circuit & Irradiation Test End
- ◆ 00. 3 AMT-1 ES chip produced
- ◆ 00.4-8 AMT-1 Circuit Test & Radiation Test.
- ◆ Summer ASD Lite -> AMT-1 -> CSM-0 Test @Boston?
- ◆ 00. 9? Design Review
- ◆ 01. 1 AMT-2 (2nd Prototype Chip) will be submitted
- ◆ 01. 6? Production Readiness Review
- ◆ 01. 9 AMT mass production start
- ◆ 02. 1 AMT mass production end

## Summary

- AMT-1 has been tested and no major problem was found yet.
- PLL jitter become large at some frequency, but still good enough for MDT ( $\sigma_{\text{total}} \sim 270\text{ps}$ ).
- Power consumption was much lower ( $\sim 20\text{mW/ch}$ ) than simulation value. More reduction is expected in AMT-2 due to new LVDS receiver.
- Preliminary User's manual is available from <http://atlas.kek.jp/~araiy/> .
- Total test with ASD and CSC will be planned.